

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Application Number		10573236	
	Filing Date		2008-08-18	
	First Named Inventor	Walter Aldred		
	Art Unit	2856		
	Examiner Name	Robert Raevis		
	Attorney Docket Number	57.0598 US PCT		

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1	BORDAKOV et al, "A new methodology for effectively correcting LWD depth measurements", EAGE 69th Conference and Exhibition, London, UK, 11-14 June 2007, paper D048	<input type="checkbox"/>
2	CHIA et al, "A new method for improving LWD logging depth", SPE Annual Technical; Conference and Exhibition, San Antonio, Texas, USA, 24-27 September 2006, SPE 102175	<input type="checkbox"/>
3	DASHEVSKIY et al, "Dynamic depth correction to reduce depth uncertainty and improve MWD/LWD log quality", SPE Annual Technical Conference and Exhibition, San Antonio, Texas, USA 24-27 September 2006, SPE 103094	<input type="checkbox"/>

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